

METHOD AND SYSTEM FOR DISTRIBUTED TESTING
OF ELECTRONIC DEVICES

ABSTRACT OF THE DISCLOSURE

0956541.092701
5 A distributed tester method and system communicates
test recipes for testing electronic devices from a host
computer over a network to a test site. The test site
translates test recipes into test instructions for
execution by a test engine that determines the status of
the electronic device. For instance, in a tester for
testing memory, a test recipe is defined and stored with
a host computer to determine test data for storage on the
10 memory device under test at the test site. The host
computer controls execution of the test recipe over the
network. The test recipe is defined and stored in an XML
formatted data file transmitted over the network to a
processor at the test site. The test site processor
15 translates the XML formatted data into test instructions
for execution by a test engine. The test engine
determines whether the memory device under test
accurately stores data and provides the results, such as
erroneously stored data, to the host computer through the
20 network. A test design host and a global data master
also interface with the network to aid the design and
storage of test recipes. The distributed test method and
system advantageously improves flexibility of testing
over a geographically disbursed area and with divergent
25 test recipes and devices under test.